

A device for quantitative assessment of the aligned position of two machine parts, workpieces or the like is used especially for purposes of axis alignment or spindle alignment. A light beam is incident on an optoelectronic sensor which can be read out two-dimensionally and the impact point there is determined by the sensor. Part of the light beam is preferably reflected by the sensor directly onto a second optoelectronic sensor. The impact point of the reflected light beam there is determined in a feasible manner by the second sensor. The orientation of at least the first sensor relative to the location of the light beam is determined from the signals of the two sensors.

[illegible]